Short Term Plan

April 21, 2023

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- Establish pre-measurement routine for the day.
 - Check RACK power status
 - Check cooling
- Establish summary report of the day format. (Cheng-Wei & Genki)
- Complete all S&N ROC calibration and address in newly discovered problem in the latest data. (Cheng-Wei)
- LV/Bias monitor (plot voltage/current as a function of time) to be developed within ignition scheme for LV.

Data Taking Plan

- Noise data for all ROCs by self-trigger. (3hours)
 - Noise study with light on/off for a few ROCs. DAC0=15. (1hour)
- DAC0 scan for noise rate study (3hours)
- DAC scan (First attempt to observe MIP in IR) with self-trigger mode. (3hours)
- Test 2 vs 1 ROCs modes calibration data taking with the latest DAQ version. (1h)
 - Make sure no difference in results between two modes.
- Take calib data North and South fibers together in 2 ROCs mode. (1h)
 - Make sure nothing odd happen.

Check List for the daily measurements

- Establish pre-measurement routine for the day.
 - Check RACK power status
 - Check cooling (30GPH/ROC, 10GPH/ladder), GUI is under bug fix by Steve and Rob.
 - Let shift leader know the activities. (make e-log entry at the end)

PRR 3.2	PRR 4.1	PRR 4.2
1E1	1E2	1E3
1W1	1W2	1W3
2E1	2E2	2E3
2W1	2W2	2W3
3A1	3B1	3C1
3A2	3B2	3C2
3A3	383	3C3
3A4	3B4	3C4
3A5	3B5	3C5
3A6	3B6	3C6
	387	3C7
	3B8	3C8
	389	3C9





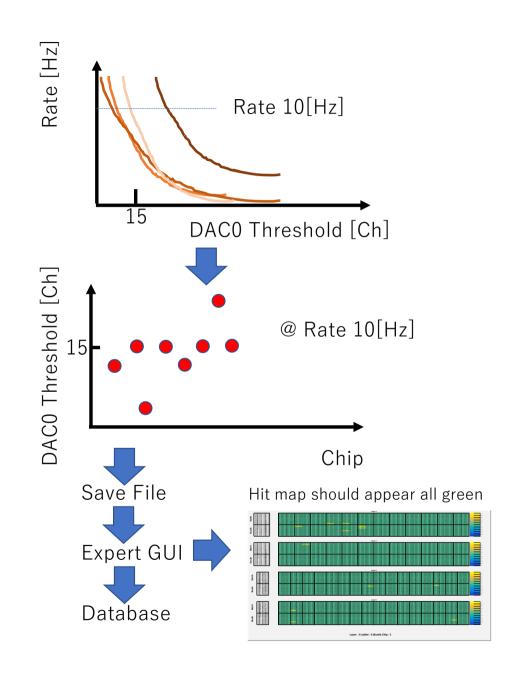




DACO Scan

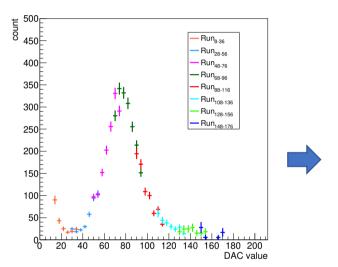
- Scan DAC0 value one-by-one [20, 19, 18, 17, ···] w/ self-trigger.
- Need develop analysis software to evaluate rates/chip.
- Optimize the DAC0 threshold for each Chip to give the same given rate. Save threshold values (52 x 56) in file loadable to Expert GUI.
- Customize DAC0 threshold setting chip-by-chip (Expert-GUI)
- This is the practice for the DAC0 threshold scan with the beam during commissioning. (S/N is also considered w/ beam)

Joseph develops data converter to feed non-prdf data to the online monitor

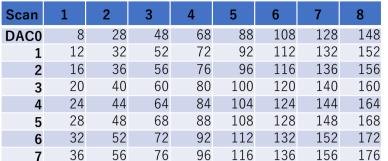


DAC Scan

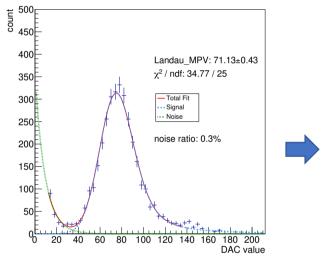
w/ Cosmic Ray w/ self-trigger



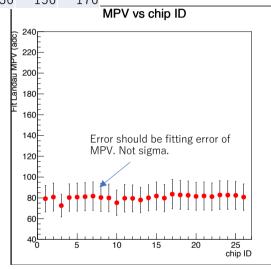
- Chip-by-Chip Base
- Clustering (Optimize offset value)
- Normalization btwn adjacent runs
- Concatenate all runs



Analyzer:
onsite quick analysis
+ Yuka for detail?



 Fitting with Landau+Gaussian convolution function.



Half ladder by half ladder



All ladders

Save all fitting parameters: MPV, Width, ...

RCDAQ on Felix developments ···

- Raul's test is the highest priority. Raul can test whenever he needs. Other data taking will be carried out while he is not doing test in IR.
- Raul works on the GTM integration and test it on Monday afternoon.
- Long time (~10 hours) high threshold noise data taking (optimize threshold not to get the file too big) for the stability test of the optical link. Genki will execute while his shift on Monday.